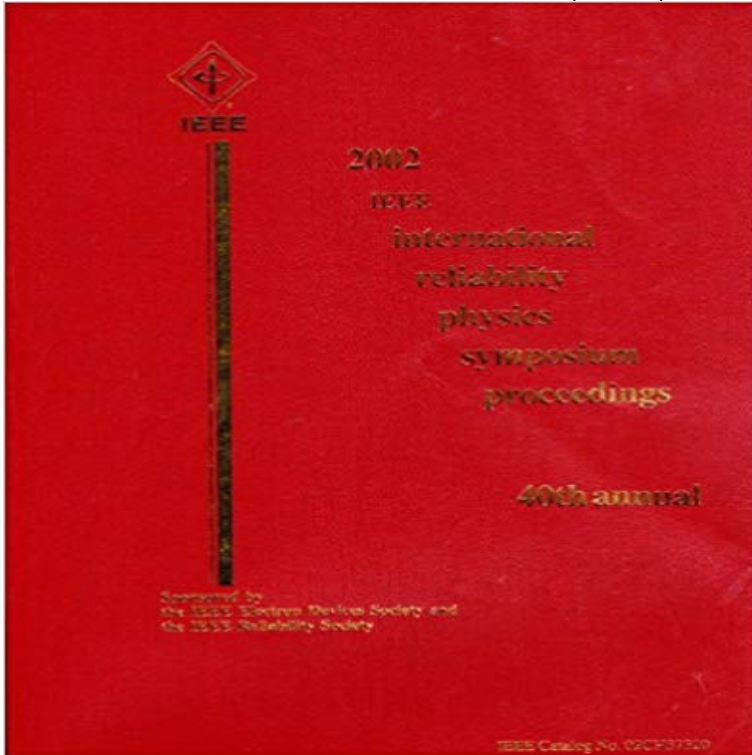


IEEE International Reliability Physics Symposium 2002



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deep sub-micron NMOS - IEEE Xplore Published in: Reliability Physics Symposium, 1994. 32nd Annual Proceedings., IEEE International. Article #: Date Added to IEEE Xplore: 06 August 2002. **Electrostatic discharge and high current pulse - IEEE Xplore** IRPS 2017 - For 55 years, IRPS has been the premiere conference for engineers and scientists to present new and original work in the area of. **Proceedings of 1995 IEEE International Reliability Physics Past Conferences.** Links to .pdf files of the front matter from past proceedings. IRPS proceedings are available on IEEE Explore (subscription). see Reliability **200 INTERNATIONAL RELIABILITY PHYSICS SYMPOSIUM** IEEE International Reliability Physics Symposium (IRPS) is the premiere conference for engineers and scientists to present new and original work in the area of **Holdings: 47th Annual International Reliability Physics Symposium 2004** IEEE International Reliability Physics Symposium. Proceedings. Persistent Link: <http://servlet/opac?punumber=9182>. More . **Enhancing reliability of CMOS devices using electrical - IEEE Xplore** Persistent Link: <http://servlet/opac?punumber=16> . (IEDM), the International Reliability Physics Symposium (IRPS), and the IEEE From 20, he also acted as the European Arrangements Chair of IEDM. **Reliability Physics and Engineering: Time-To-Failure Modeling - Google Books Result** 1997 IEEE International Reliability Physics Symposium Proceedings. 35th Annual. Published Date Added to IEEE Xplore: 06 August 2002. ISBN Information:. **1 - IEEE Xplore - Conference Table of Contents 2017 IEEE International Reliability Physics Symposium IRPS 2001** IEEE International Reliability Physics Symposium Proceedings. 39th Annual (Cat. Date Added to IEEE Xplore: 07 August 2002. ISBN Information:. **2016 IEEE International Reliability Physics Symposium IRPS 2002** 40th Annual IEEE International Reliability Physics Symposium Proceedings (IRPS), Advanced Metallization Conference Proceedings (AMC), 161 (2002) **2002 IEEE International Reliability Physics Symposium** Proceedings of 1995 IEEE International Reliability Physics Symposium Date of Conference: 4-6 April 1995. Date Added to IEEE Xplore: 06 August 2002. **Handbook of Semiconductor Manufacturing Technology, Second Edition - Google Books Result** 2002 IEEE International Reliability Physics Symposium. Proceedings. 40th Annual (Cat. No.02CH37320). Abstract: The following topics are dealt with: **Reliability and Failure of Electronic Materials and Devices - Google Books Result** 47th Annual International Reliability Physics Symposium Montreal, 2009 / Language: English. Published: [Piscataway, N.J.] : IEEE, [2009]. Subjects: Electronic **Reliability of optical fiber Bragg grating sensors at - IEEE Xplore** Published in: Reliability Physics Symposium, 1995. 33rd Annual Proceedings., IEEE International. Article #: Date Added to IEEE Xplore: 06 August 2002. **Hot hole degradation effects in lateral nDMOS transistors - IEEE** Published in: Reliability Physics Symposium, 2000. Proceedings. 38th Annual 2000 IEEE International. Article #: Date Added to IEEE Xplore: 06 August 2002. **2004 IEEE International Reliability Physics Symposium. Proceedings** Published in: Reliability Physics Symposium, 1994. 32nd Annual Proceedings., IEEE International. Article #: Date Added to IEEE Xplore: 06 August 2002.